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IN THE CLAIMS:

1. (Currently Amended) An inspecting system comprising:

an analyzing unit, said analyzing unit including an image detection device for producing a plurality of images of a workpiece;

storage means for storing said plurality of images produced by said image detection device and classification information;

display screen means having a display screen with a first display screen area for displaying said plurality of images stored in said storage means that have not been classified, and a plurality of second display screen areas ~~for displaying selected classification information and for initially~~ classifying said images according to visual features of said images; and

means for manually moving said plurality of ~~detected~~ images on said display screen from said first display screen area to selected second display screen areas to classify and display said images in said second display screen areas.

2. (Currently Amended) An analyzing unit comprising:

storage means for storing a plurality of images and classification information;

display means having a display screen with a first display screen area for displaying said plurality of images stored in said storage means that have not been classified, and a plurality of second display screen areas ~~for displaying selected classification information and for initially~~ classifying said images according to visual features of said images; and

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means for manually moving ones of said plurality of images on said display screen from said first display screen area to selected second display screen areas to classify and display said plurality of images in said second display screen areas.

3. (Currently Amended) A method of manufacturing an electronic device, wherein use is made of a manufacturing apparatus for processing a workpiece to form an electronic device, an inspecting apparatus for inspecting the workpiece processed by said manufacturing apparatus, an analyzing unit including an image detection device which is capable of producing a plurality of images of said workpiece, and a storage means for storing said images of said workpiece detected by said image detection device and ~~other~~ classification information, the method comprising:

displaying said plurality of images stored in said storage means on a first display screen area of a display screen, the display screen having a plurality of second display screen areas ~~containing selected other information~~ for classifying and displaying said ~~detected~~ images according to visual features of said images;

manually moving ones of said images on said display screen from said first display screen area to selected second display screen areas to classify and display said detected images in said second display screen areas;

providing information to said analyzing unit concerning images in said second display screen areas of said screen; and

controlling the production line having said manufacturing apparatus arranged thereon using information obtained from said analyzing unit.

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4. (Currently Amended) An inspecting system comprising:

an analyzing unit, said analyzing unit including an image detection device to produce images of semiconductor manufacturing defects for a workpiece;

a display screen with a sorting display screen area in which to display ones of said images with unclassified semiconductor manufacturing defects, and a plurality of

defect-classification display screen areas into which each image of said images may be classified and displayed according to visual manufacturing defect features

contained in the image; and

a user-manipulated moving unit to move an image from said sorting display screen area to selected ones of said defect-classification display screen areas, to classify and display said subject image in the selected ones of said defect-classification display screen areas.

5. (Currently Amended) An inspecting system as claimed in claim 4, wherein

the user-manipulated moving unit includes a user-manipulated pointing device to point to, select and drag-and-drop said image from said sorting display screen area into selected ones of said defect-classification display screen areas.

6. (Previously Presented) An inspecting system as claimed in claim 5,

wherein said user-manipulated pointing device is a mouse.

7. (Currently Amended) An inspecting system as claimed in claim 4,

comprising a memory to store predetermined information for at least ones of said

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images including defect-classification information, and an adjuster unit to automatically adjust said defect-classification information for said images to match a defect classification of the selected one of said defect-classification display screen areas to which said images are moved.

8. (Currently Amended) An inspecting method, comprising:

using an image detection device to produce images of semiconductor manufacturing defects in a workpiece;

displaying images of unclassified semiconductor manufacturing defects within a sorting display screen area of a display screen, and displaying a plurality of defect-classification display screen areas into which each image of said images may be classified and displayed according to visual manufacturing defect features contained in the images; and

user-manipulated moving of a subject image from said sorting display screen area to selected ones of said defect-classification display screen areas, to classify and display each said image in the selected one of said defect-classification display screen areas.

9. (Currently Amended) An inspecting method as claimed in claim 8, wherein said user-manipulated moving is effected with a user-manipulated pointing device to point to, select and drag-and-drop said images from said sorting display screen area into the selected ones of said defect-classification display screen areas.


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10. (Previously Presented) An inspecting method as claimed in claim 9, wherein said user-manipulated pointing device is a mouse.

11. (Currently Amended) An inspecting method as claimed in claim 8, comprising:

storing predetermined information for at least ones of said images including defect-classification information in a memory; and

 automatically adjusting said defect-classification information for said subject image to match a defect classification of the selected one of said defect-classification display screen areas to which said images are moved.

12. (New) An inspecting system as claimed in claim 1, wherein images of multiple classified ones of the images are simultaneously displayable within ones of the second display screen areas.

13. (New) An inspecting system as claimed in claim 1, comprising an data update unit to automatically update the classification information stored in the storage means, for each image manually-moved to one of the second display screen areas.

14. (New) An inspecting system as claimed in claim 1, comprising a user-classifier unit to allow user-designation of classification criteria for the plurality of second display screen areas into which each image of said images may be classified and displayed.

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15. (New) An analyzing unit as claimed in claim 2, wherein images of multiple classified ones of the images are simultaneously displayable within ones of the second display screen areas.

16. (New) An analyzing unit as claimed in claim 2, comprising an data update unit to automatically update the classification information stored in the storage means, for each image manually-moved to one of the second display screen areas.

17. (New) An analyzing unit as claimed in claim 2, comprising a user-classifier unit to allow user-designation of classification criteria for the plurality of second display screen areas into which each image of said images may be classified and displayed.

18. (New) A method as claimed in claim 3, wherein images of multiple classified ones of the images are simultaneously displayable within ones of the second display screen areas.

19. (New) A method as claimed in claim 3, comprising automatically updating the classification information stored in the storage means, for each image manually-moved to one of the second display screen areas.

20. (New) A method as claimed in claim 3, comprising allowing user-designation of classification criteria for the plurality of second display screen areas into which each image of said images may be classified and displayed.

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21. (New) An inspecting system as claimed in claim 4, wherein images of multiple classified ones of the images are simultaneously displayable within ones of the defect-classification display screen areas.

22. (New) An inspecting system as claimed in claim 4, comprising a user-classifier unit to allow user-designation of classification criteria for the plurality of defect-classification display screen areas into which each image of said images may be classified and displayed.

23. (New) An inspecting system as claimed in claim 4, wherein the user-manipulated moving unit is also to move a previously classified image from one of said defect-classification display screen areas to a differing one of said defect-classification display screen areas, to reclassify and display said classified image in the differing one of said defect-classification display screen areas.

24. (New) An inspecting method as claimed in claim 8, wherein images of multiple classified ones of the images are simultaneously displayable within ones of the defect-classification display screen areas.

25. (New) An inspecting method as claimed in claim 8, comprising allowing user-designation of classification criteria for the plurality of defect-classification display screen areas into which each image of said images may be classified and displayed.

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26. (New) An inspecting method as claimed in claim 8, comprising moving a previously classified image from one of said defect-classification display screen areas to a differing one of said defect-classification display screen areas, to reclassify and display said classified image in the differing one of said defect-classification display screen areas.

27. (New) An inspecting system comprising:

an analyzing unit, said analyzing unit including an image detection device to produce images of semiconductor manufacturing defects for a workpiece;

a display screen for displaying a sorting display screen area in which plural ones of said images with unclassified semiconductor manufacturing defects are displayable, and simultaneously displaying a plurality of defect-classification display screen areas into which each image of said images may be classified according to visual manufacturing defect features contained in the image; and

a user-manipulated moving unit to move an image from said sorting display screen area to selected ones of said defect-classification display screen areas, to classify and display said subject image in the selected ones of said defect-classification display screen areas;

wherein images of multiple classified ones of said images are simultaneously displayable within ones of the defect-classification display screen areas.

28. (New) An inspecting system as claimed in claim 27, wherein said user-manipulated moving unit includes a mouse.

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29. (New) An inspecting system as claimed in claim 27, comprising a memory to store predetermined information for at least ones of said images including defect-classification information, and an adjuster unit to automatically adjust said defect-classification information for said images to match a defect classification of the selected one of said defect-classification display screen areas to which said images are moved.

30. (New) An inspecting system as claimed in claim 27, wherein the user-manipulated moving unit is also to move a previously classified image from one of said defect-classification display screen areas to a differing one of said defect-classification display screen areas, to reclassify and display said classified image in the differing one of said defect-classification display screen areas.

31. (New) An inspecting method comprising:
using an image detection device to produce images of semiconductor manufacturing defects for a workpiece;
displaying a sorting display screen area in which plural ones of said images with unclassified semiconductor manufacturing defects are displayable, and simultaneously displaying a plurality of defect-classification display screen areas into which each image of said images may be classified according to visual manufacturing defect features contained in the image; and
user-manipulated moving an image from said sorting display screen area to selected ones of said defect-classification display screen areas, to classify and

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display said subject image in the selected ones of said defect-classification display screen areas;

wherein images of multiple classified ones of said images are simultaneously displayable within ones of the defect-classification display screen areas.

32. (New) An inspecting method as claimed in claim 31, wherein said user-manipulated moving is effected with a mouse.

33. (New) An inspecting method as claimed in claim 31, comprising storing predetermined information for at least ones of said images including defect-classification information, and automatically adjusting said defect-classification information for said images to match a defect classification of the selected one of said defect-classification display screen areas to which said images are moved.

34. (New) An inspecting method as claimed in claim 31, comprising moving a previously classified image from one of said defect-classification display screen areas to a differing one of said defect-classification display screen areas, to reclassify and display said classified image in the differing one of said defect-classification display screen areas.